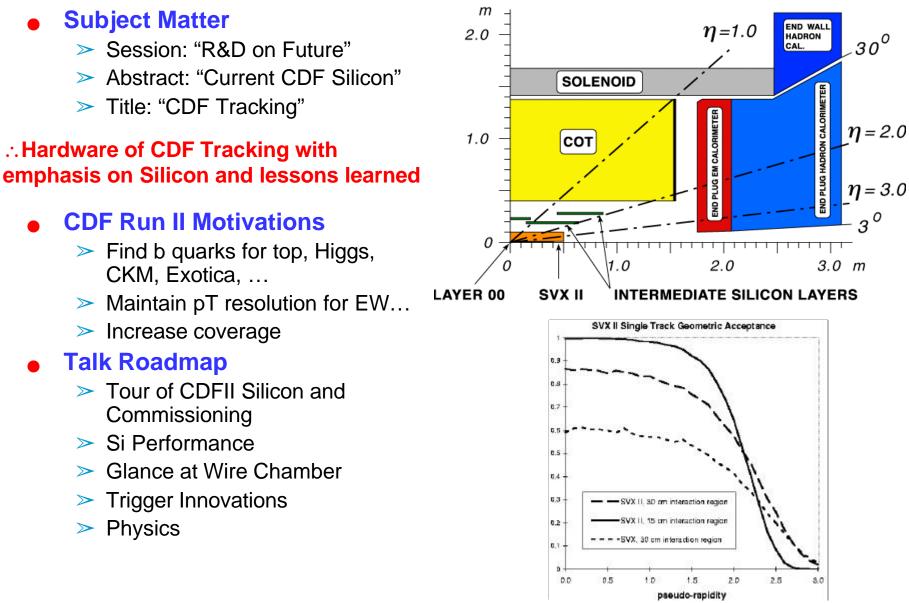


Status of CDF Tracking

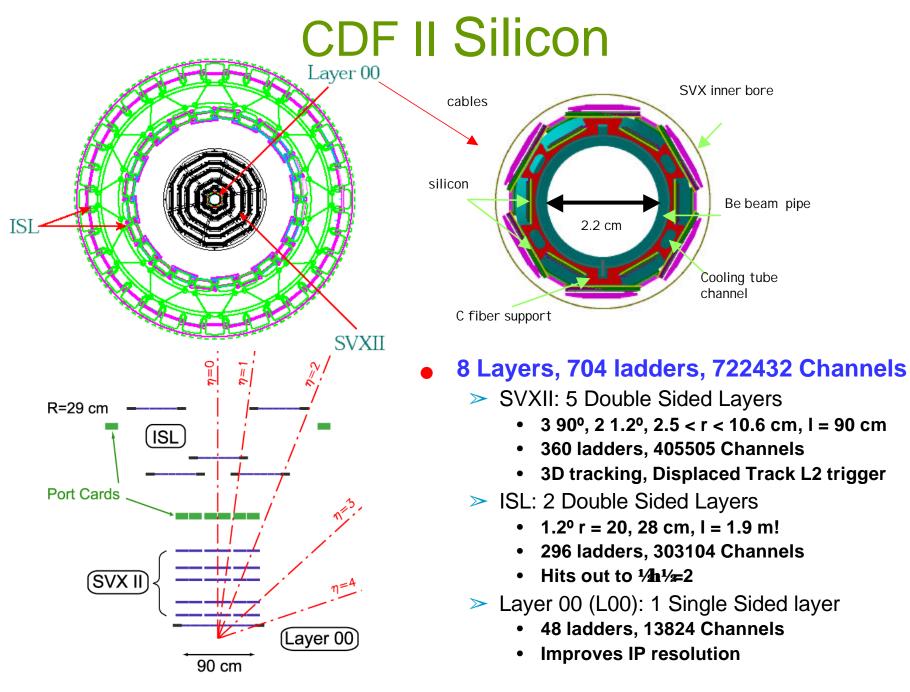
Steve Nahn Yale University/CDF

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CDF Run II Tracking

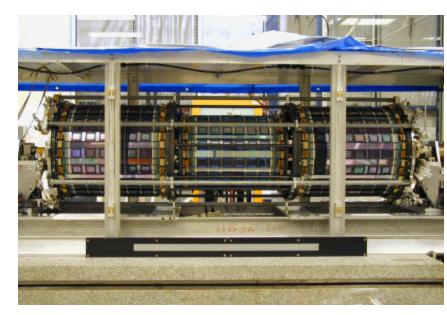


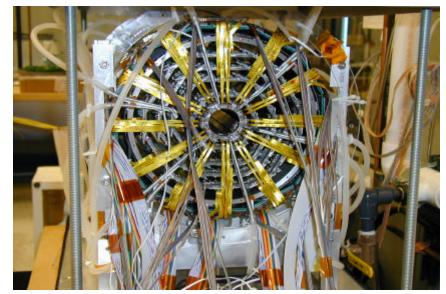
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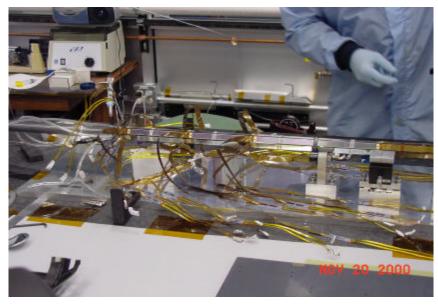
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Construction Pictures









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ICHEP Parallel Session 13

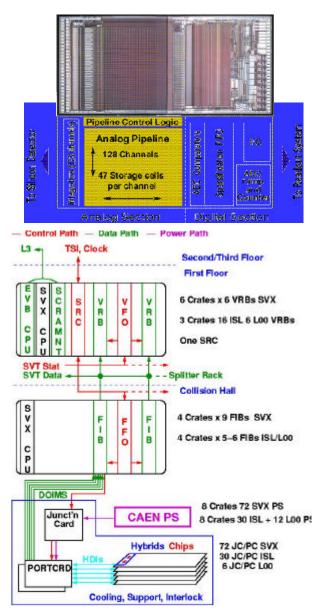
Si DAQ (common)

SVX3D Chip

- > 128 Ch x 46 Capacitor Ring
- "Deadtimeless"-Acquires during Readout
- Features: Common Noise suppression, Sparsification...

Portcards

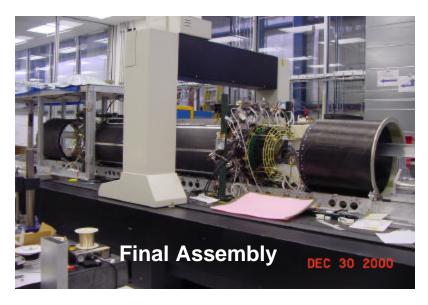
- ➤ Control: 1⇒5 Fanout
- > Data: Electrical \Rightarrow Optical
- Custom VME DAQ and PS
- Cooling, Interlocks, Radiation Protection, etc

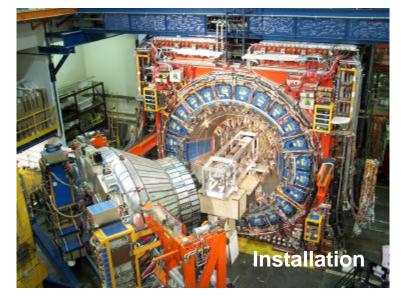


Silicon Integration and Installation





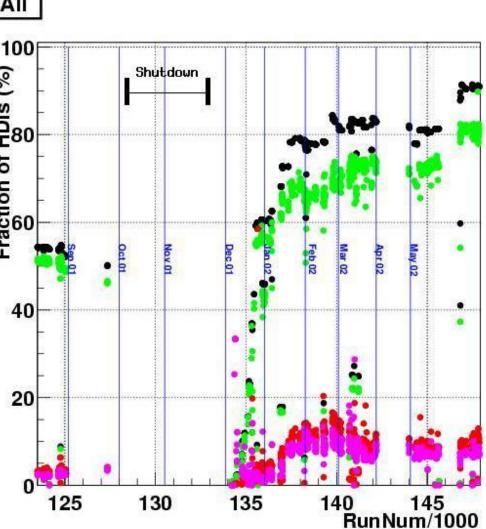




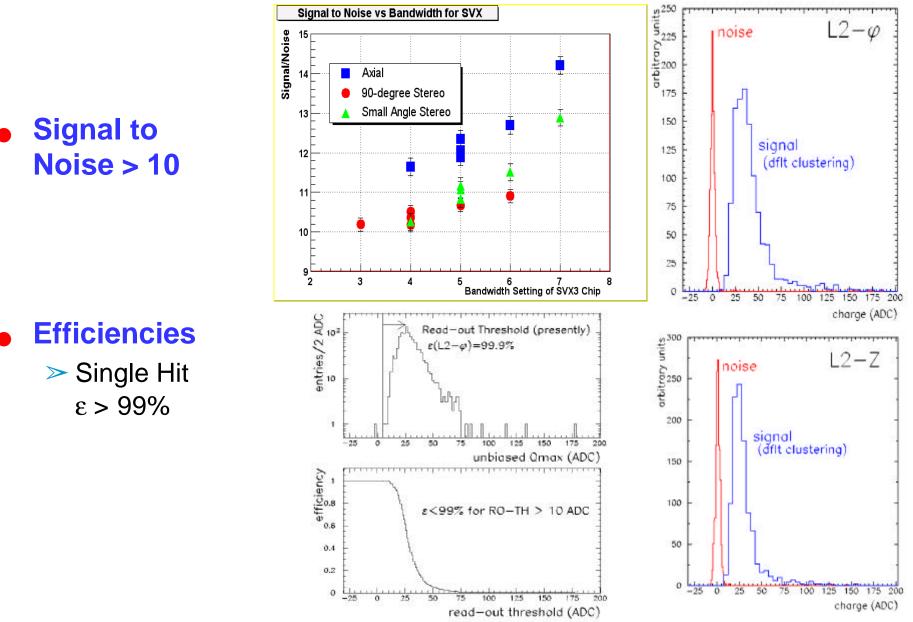
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Silicon Commissioning Issues

Vendors All > Delay, failure of PS 100 **Relentlessly Pursue** Fraction of HDIs (%) **Realistic Testing** > ISL blocked cooling > L00 noise issues > Optical problems Get to operating conditions ASAP Beam 40 > Chip Damage > VME PS failure Characterize failure modes before 20 Installation Currently 90%/80% and stable

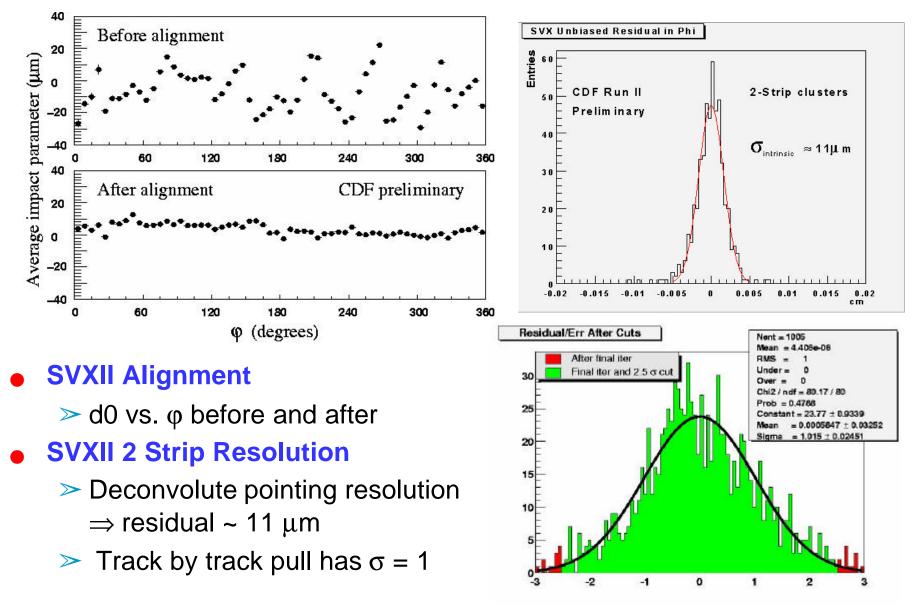


Performance of Silicon (1)



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Silicon Performance(2)

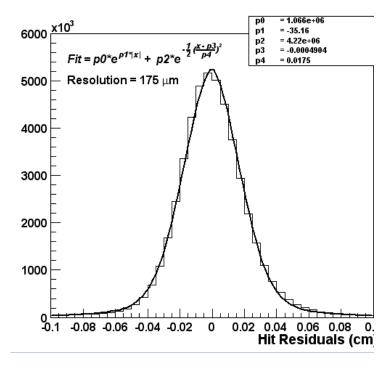


CDF Central Outer Tracker

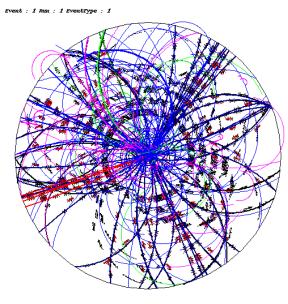
• More Hits on tracks

- > 5x Run I sense wires
- > 2x Run I Stereo layers
- Uniform Drift Field

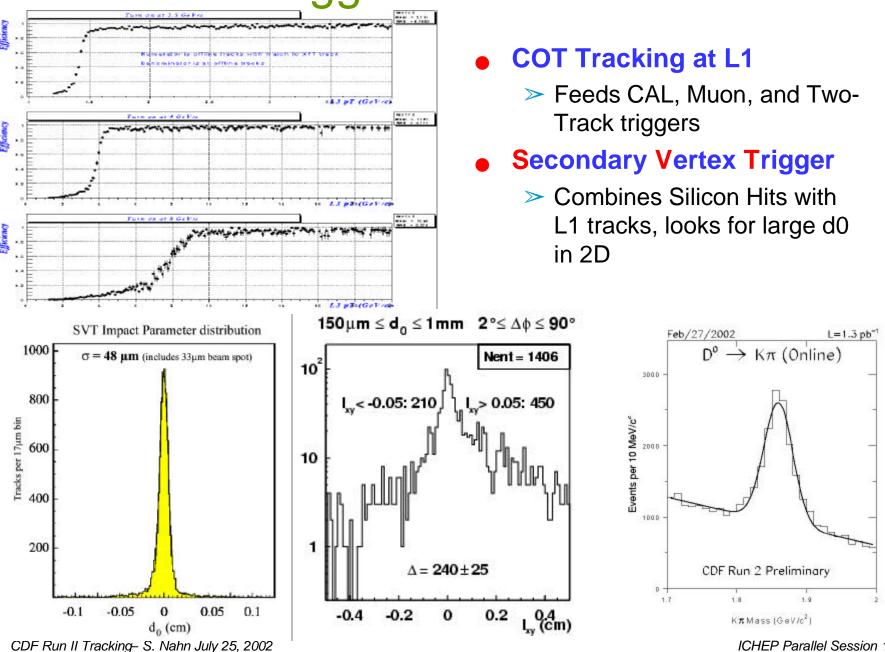
Maintain Run I momentum resolution



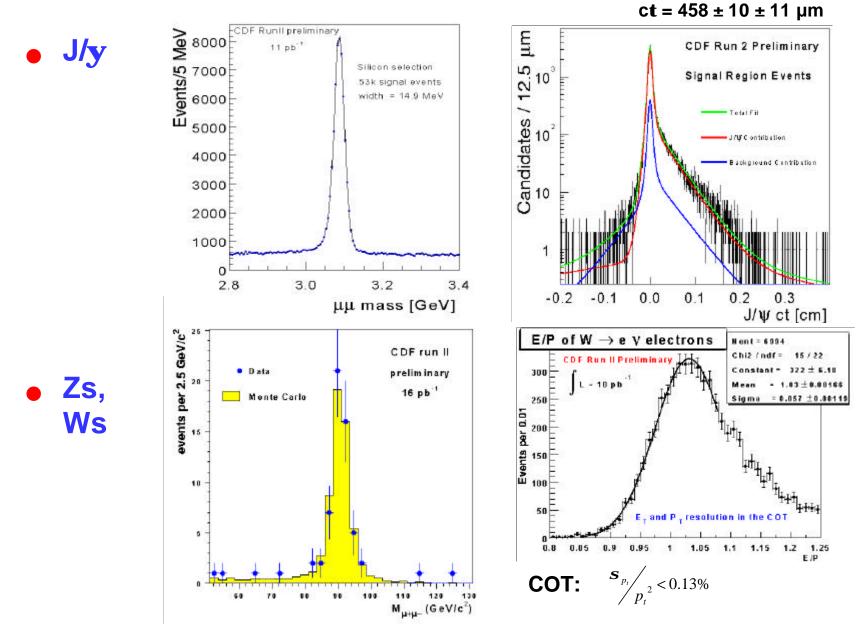




Trigger Innovations

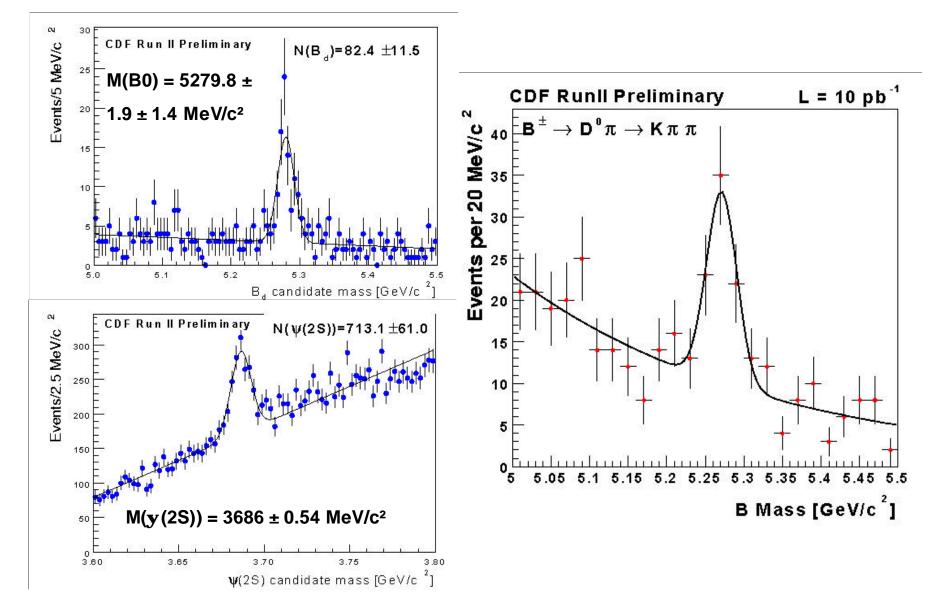


Calibration from Physics



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B Physics from CDFII



Summary

• CDF Run II tracking performing well

- > Si detector is producing clusters and tracks
- > Trigger innovations enhancing physics content of data
- > CDF tracking-based results being presented at ICHEP2002

• Light at the End of the Tunnel...

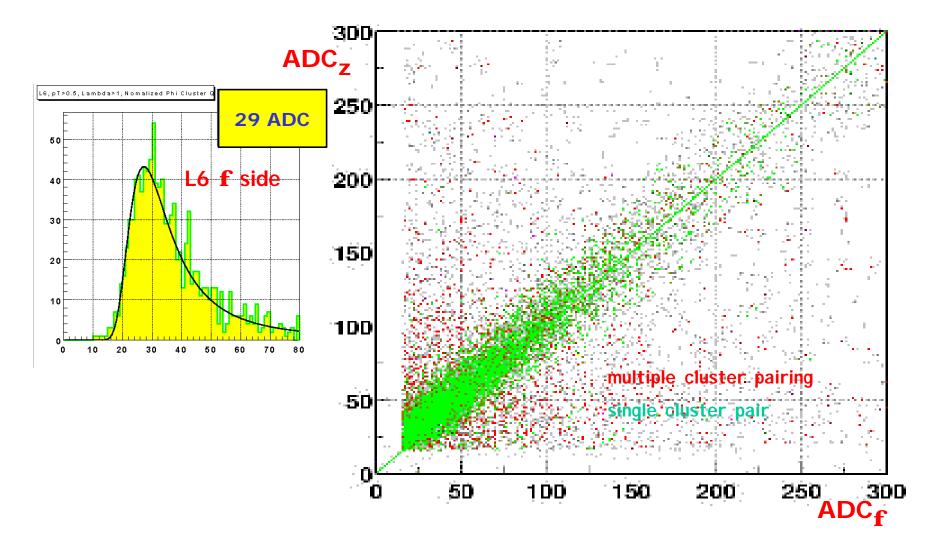
- > Exiting Commissioning phase, entering Maintenance
- > Getting to the small and subtle problems is progress
- Lessons learned about vendor dependencies, realistic testing, and probing failure modes while not entombed

• Still fair amount of work yet to do

- > Most of the remaining problems are the hard ones...
- > New things appear from time to time

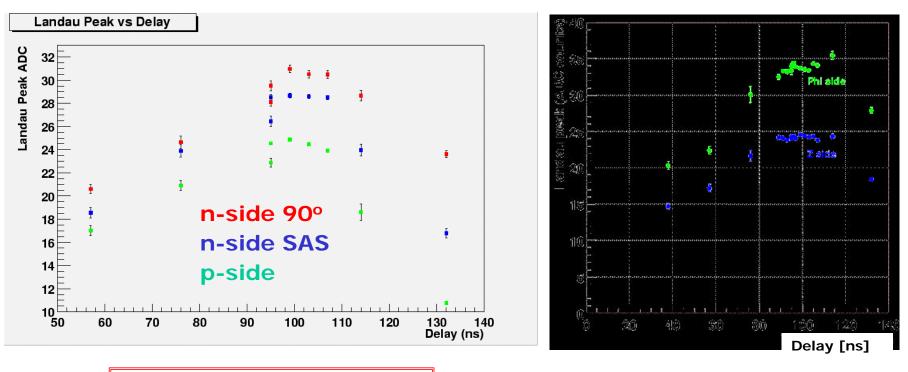
Support Slides Follow this one

Charge correlation (ISL)



Timing scan results

ISL

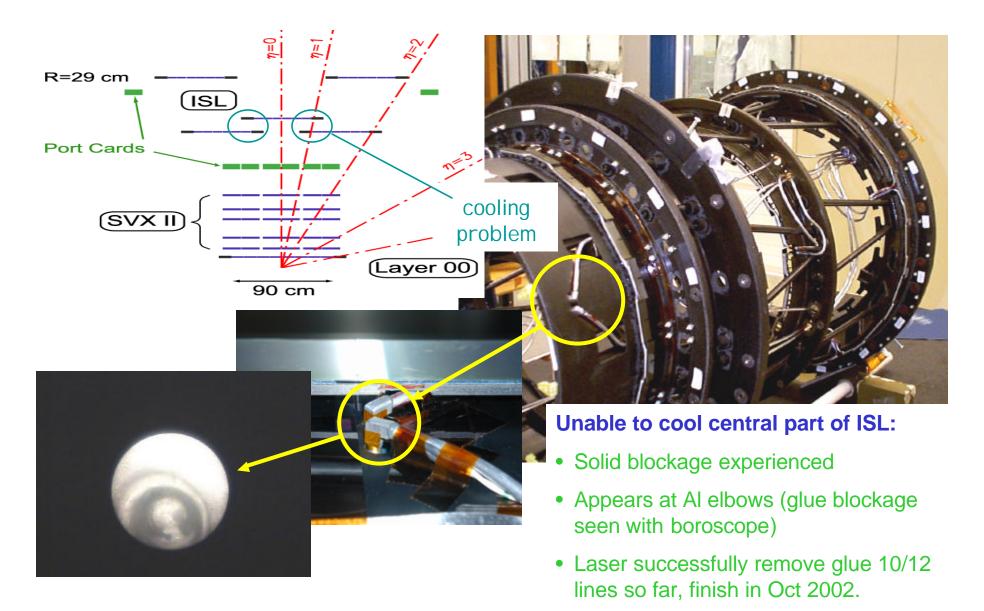


All detector types peak at roughly the same timing!

SVXII

(n- & p-side responses different here due to timing problem in FIB sequence, later fixed.)

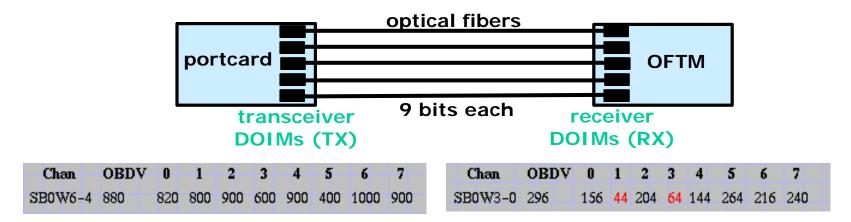
ISL Cooling Problem



Optical Problems

- Largest single source of problems
- Time consuming to fix (requires Access)
 - > Light Level too low: Increase voltage
 - Caviat: voltage shared by 5 ladders x 9 bits
 - > Light Level too high: Introduce attenuation
 - Caviat: Attenuation shared by 9 bits
 - > Light level OK: Bad connectivity of TX

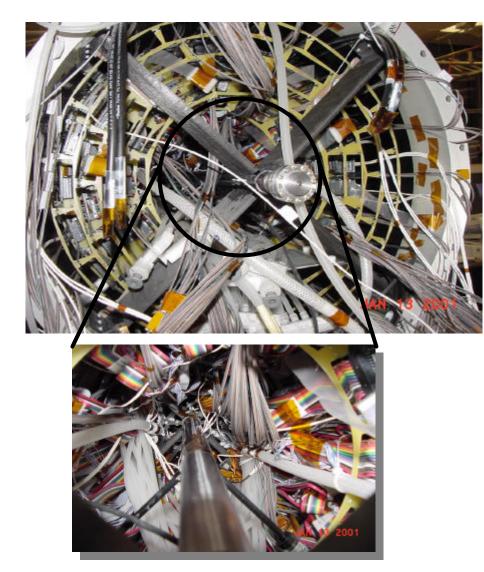
• Solutions at the RX side are being implemented



Beam Incidents

- During Oct 01 Shutdown, found new failure mode consistent with Analog power not getting to a chip on a ladder
 - Suspected thermal cycles mechanically breaking connection, or perhaps anomalous high current states blowing bonds
- March 30, 2002 Beam incident damages 6 single chips on 6 different ladders in a similar fashion
 - > Saw high currents on other voltage lines etc
 - > Suspect high **DOSE RATE** causes failure
- Test beam tests failed to reproduce the symptoms
 - > Fell back to "Only the strong survive"
 - Required new interlocks on Beam and tighter constraints on beam conditions for safe operation

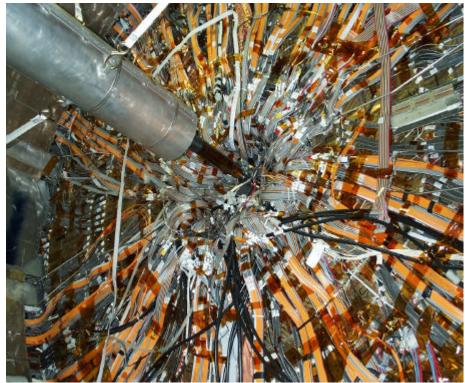
Connecting the full detector



Intensive pre-testing of cables, power supplies, optical components, cooling and interlocks took place before connection of the real detector... nonetheless:

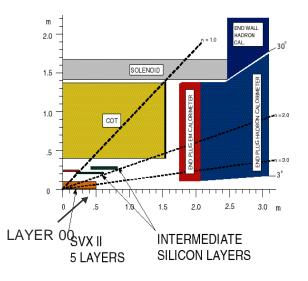


Connecting the full detector took 7 weeks, 24 hrs/day, 4 people at a time!

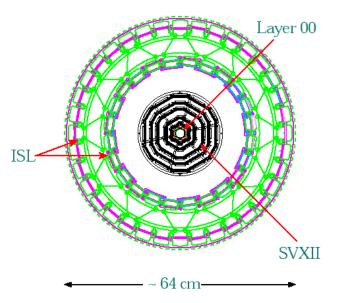


CDF Run IIa Silicon

Layer	Inner/Outer Radii [cm]	Axial Pitch [µm]	Stereo Angle	Stereo Pitch [µm]
00	1.35/1.62	25	-	-
0	2.5/3.0	60	90	141
1	4.1/4.6	62	90	125.5
2	6.5/7.0	60	1.2	60
3	8.2/8.7	60	90	141
4	10.1/10.6	65	1.2	65
5 Forward	19.7/20.2	112	1.2	112
5 Central	22.6/23.1	112	1.2	112
6 Forward	28.6/29.0	112	1.2	112

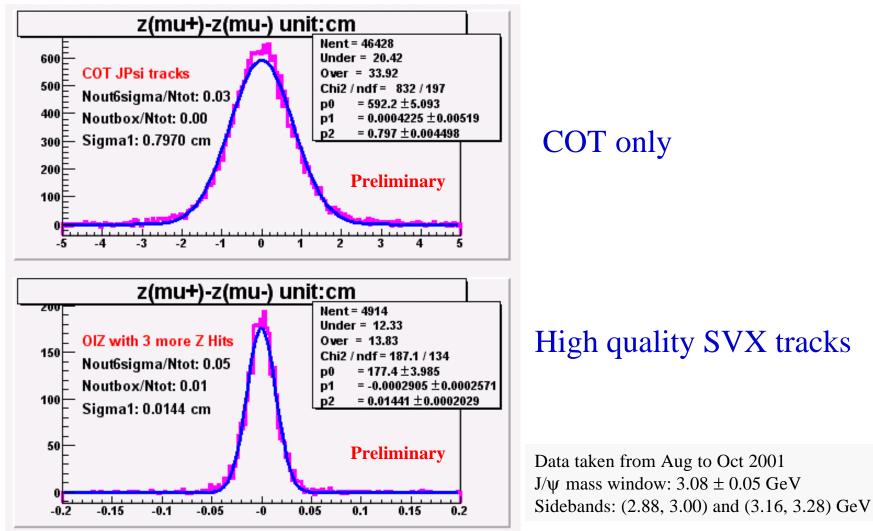


CDF	Layer 00	SVX II	ISL	Totals
Layers	1	5	2	8
Length	0.9 m	0.9 m	1.9 m	
Channels	13824	405504	303104	722432
Modules	48 SS	360 DS	296 DS	704
Readout Length	14.8 cm	14.5 cm	21.5 cm	
Inner Radius	1.35 cm	2.5 cm	20 cm	1.35 cm
Outer Radius	1.65 cm	10.6 cm	28 cm	28 cm
Power	~100 W	1.4 kW	1.0 kW	2.5 kW



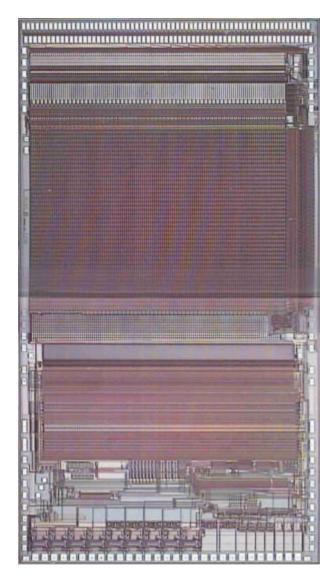
Z Resolution

$\triangle z$ distributions for $J/\psi \rightarrow \mu\mu$ tracks



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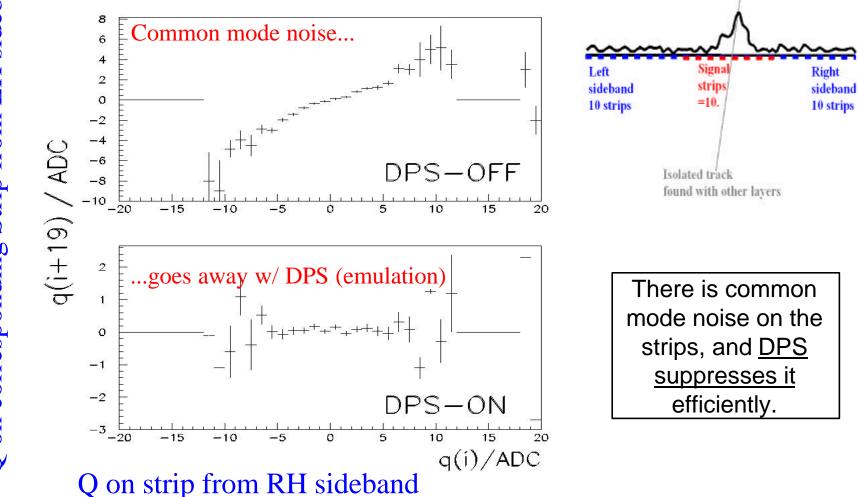
SVX3D ASIC



- 128 input channels
- Designed to operate with 132 or 396 ns beam crossing rate
- ENC = 700 + 53 electrons/pF
- 46 cell analog pipeline
- Buffers up to 4 events
- 8-bit Wilkinson ADC, digital readout
- Deadtimeless operation
- On-chip sparsification and common mode noise suppression
- Fabricated in the Honeywell
 0.8µm radiation hard process

Dynamic Common Mode Suppresion works as designed

long range charge correlations: $L2(\varphi-side)$



Measurement of Radiation Dose

- May Oct 2001 running
- Collision dominated, but losses still present
- Measurements found radial and z dependence of dose
- Radial dependence fit to $1/R^{\alpha}$ scaling
- Result: $\alpha(z) = 1.5 2.0$
- Run IIa lifetime estimates assumed α = 1.7 ± 30% (OK)

